

## Description

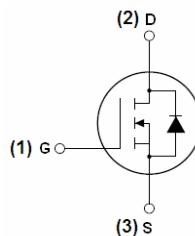
The VSM30N10 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

## General Features

- $V_{DS} = 100V, I_D = 30A$
- $R_{DS(ON)} < 32m\Omega @ V_{GS}=10V$  (Typ:25mΩ)
- Special process technology for high ESD capability
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation

## Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM30N10-TC	VSM30N10	TO-220C	-	-	-

## Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	30	A
Drain Current-Continuous( $T_c=100^\circ C$ )	$I_D (100^\circ C)$	21	A
Pulsed Drain Current <sup>(Note 1)</sup>	$I_{DM}$	120	A
Maximum Power Dissipation	$P_D$	85	W
Derating factor		0.57	W/ $^\circ C$
Single pulse avalanche energy <sup>(Note 5)</sup>	$E_{AS}$	200	mJ
$V_{DS}$ Spike <sup>(Note 6)</sup>	10μs	120	V
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 175	°C

## Thermal Characteristic

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{\theta JC}$	1.8	°C/W
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**Electrical Characteristics ( $T_c=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Condition	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	100	115	-	V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=100\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Body Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b> <sup>(Note 3)</sup>						
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1.3	1.9	2.5	V
$\text{R}_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=10\text{A}$	-	25	32	$\text{m}\Omega$
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=10\text{A}$	-	15	-	S
<b>Dynamic Characteristics</b> <sup>(Note 4)</sup>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{DS}}=50\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{F}=1.0\text{MHz}$	-	2479	-	PF
$\text{C}_{\text{oss}}$	Output Capacitance		-	96	-	PF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance		-	79	-	PF
<b>Switching Characteristics</b> <sup>(Note 4)</sup>						
$t_{\text{d(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DD}}=50\text{V}, \text{R}_{\text{L}}=5\Omega$ $\text{V}_{\text{GS}}=10\text{V}, \text{R}_{\text{GEN}}=3\Omega$	-	9	-	nS
$t_r$	Turn-on Rise Time		-	9	-	nS
$t_{\text{d(off)}}$	Turn-Off Delay Time		-	32	-	nS
$t_f$	Turn-Off Fall Time		-	8	-	nS
$Q_g$	Total Gate Charge	$\text{V}_{\text{DS}}=50\text{V}, \text{I}_D=10\text{A}, \text{V}_{\text{GS}}=10\text{V}$	-	67.2	-	nC
$Q_{\text{gs}}$	Gate-Source Charge		-	9.4	-	nC
$Q_{\text{gd}}$	Gate-Drain Charge		-	15.5	-	nC
<b>Drain-Source Diode Characteristics</b>						
$\text{V}_{\text{SD}}$	Diode Forward Voltage <sup>(Note 3)</sup>	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=10\text{A}$	-	-	1.2	V
$\text{I}_s$	Diode Forward Current <sup>(Note 2)</sup>	-	-	-	30	A
$t_{\text{rr}}$	Reverse Recovery Time	$\text{T}_j = 25^\circ\text{C}, \text{IF} = 10\text{A}$ $\text{di}/\text{dt} = 100\text{A}/\mu\text{s}$ <sup>(Note 3)</sup>	-	32	-	nS
$\text{Q}_{\text{rr}}$	Reverse Recovery Charge		-	53	-	nC
$t_{\text{on}}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

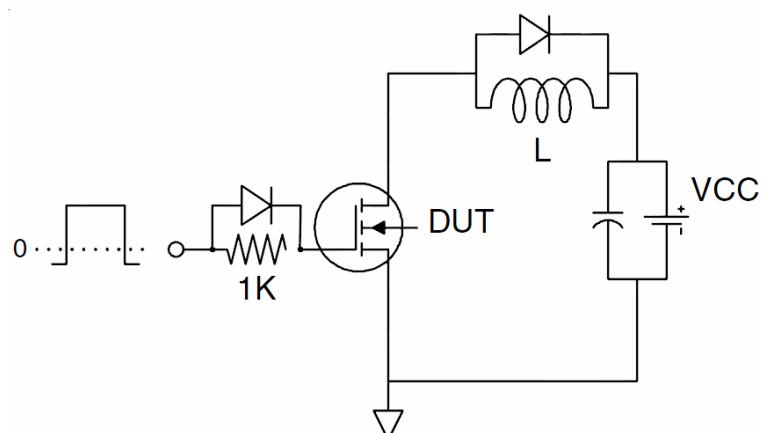
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board,  $t \leq 10$  sec.
3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
4. Guaranteed by design, not subject to production
5. EAS Condition :  $\text{T}_j=25^\circ\text{C}, \text{V}_{\text{DD}}=50\text{V}, \text{V}_{\text{G}}=10\text{V}, \text{L}=0.5\text{mH}, \text{R}_g=25\Omega$
6. The spike duty cycle 5% max, limited by junction temperature  $\text{T}_j(\text{MAX})=125^\circ\text{C}$

## Test Circuit

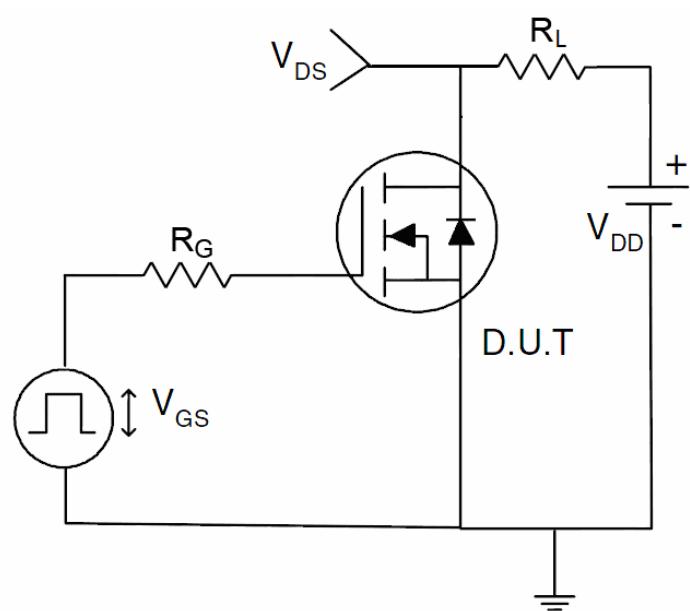
### 1) E<sub>AS</sub> Test Circuit



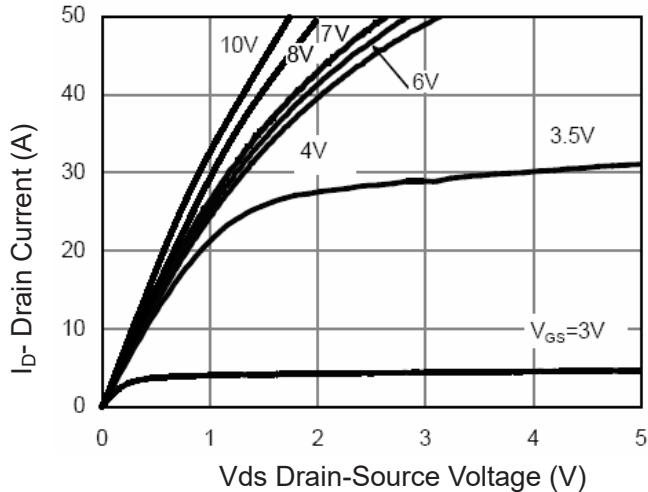
### 2) Gate Charge Test Circuit



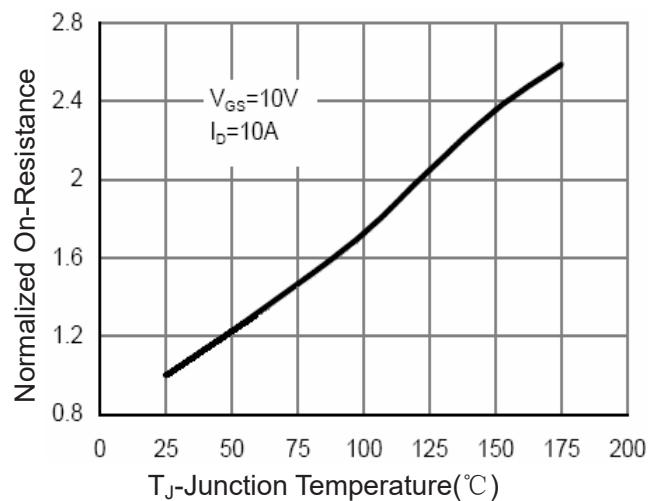
### 3) Switch Time Test Circuit



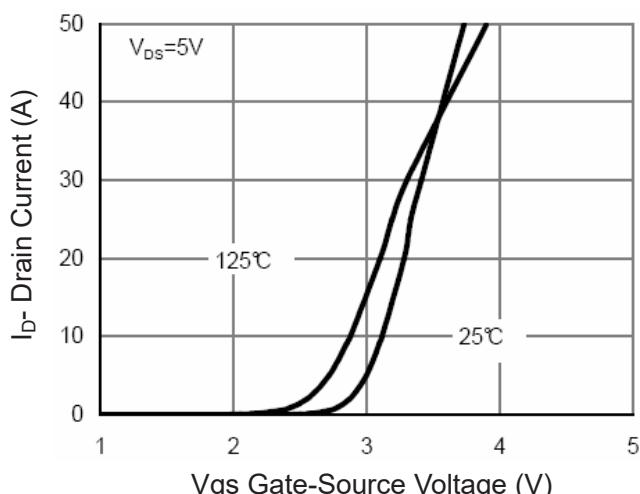
## Typical Electrical and Thermal Characteristics (Curves)



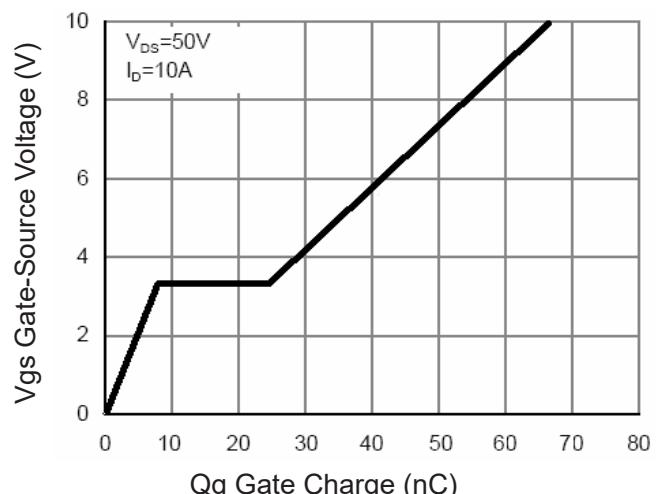
**Figure 1 Output Characteristics**



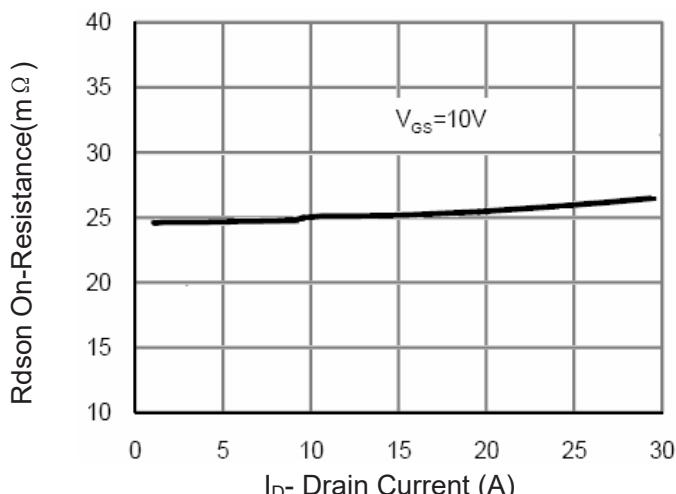
**Figure 4 Rdson-JunctionTemperature**



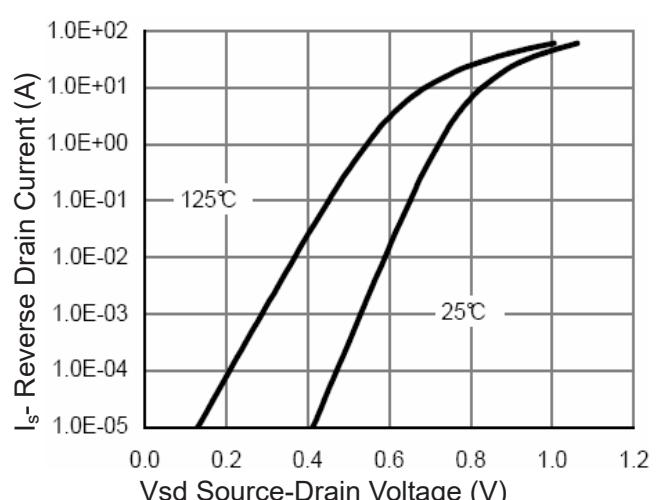
**Figure 2 Transfer Characteristics**



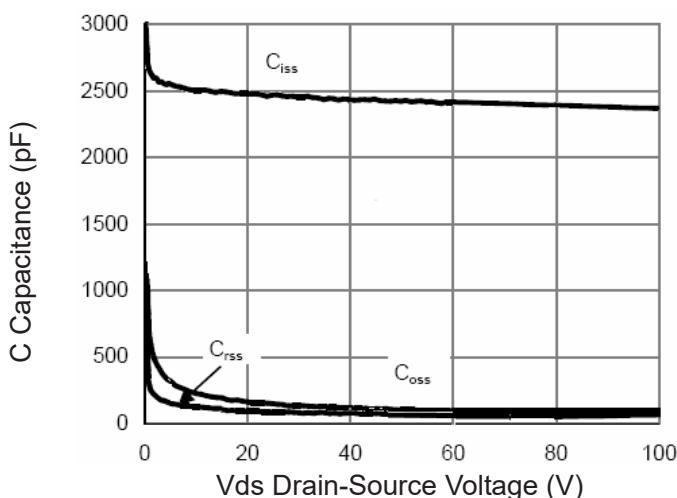
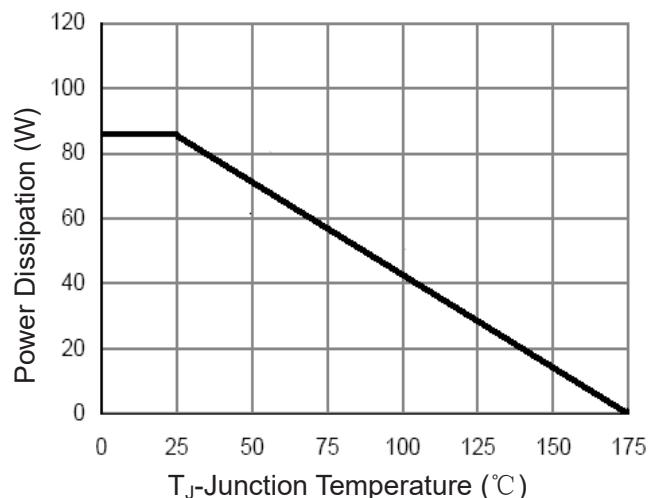
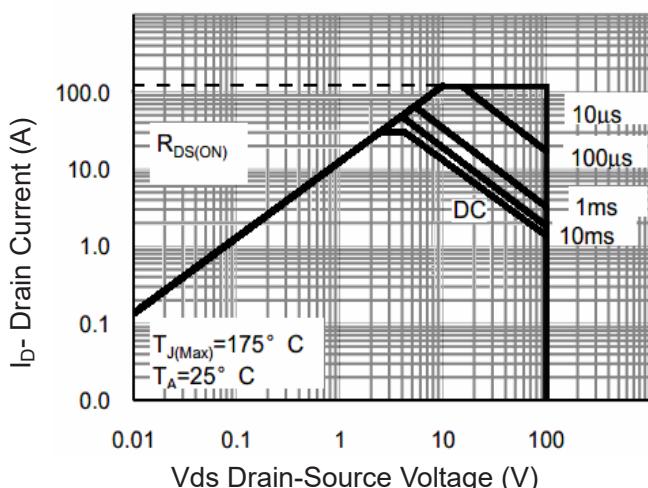
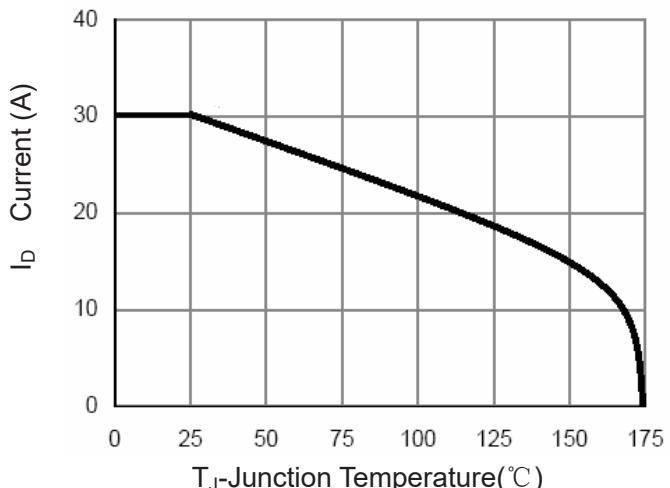
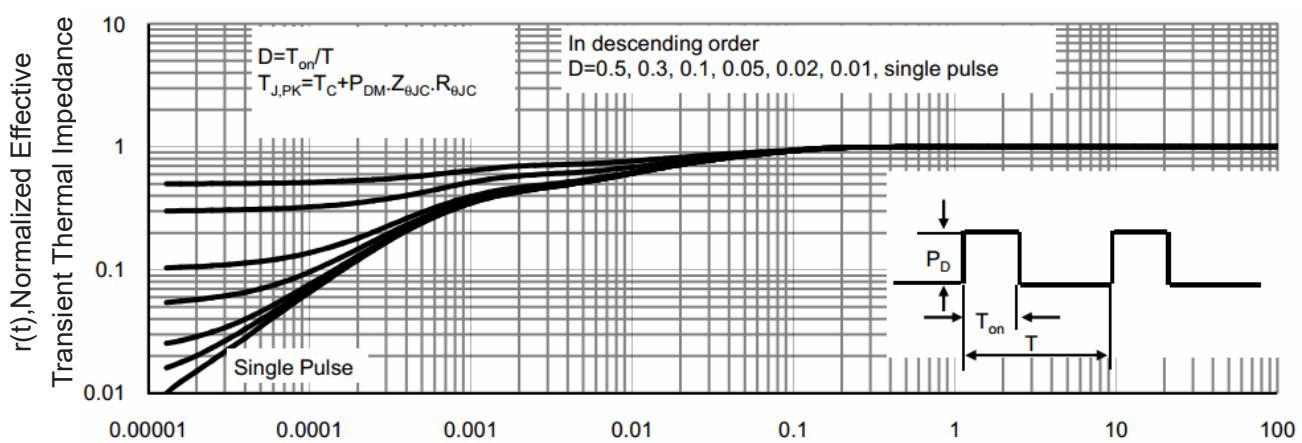
**Figure 5 Gate Charge**



**Figure 3 Rdson- Drain Current**



**Figure 6 Source- Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9 Power De-rating**

**Figure 8 Safe Operation Area**

**Figure 10 ID Current- Junction Temperature**

**Figure 11 Normalized Maximum Transient Thermal Impedance**